

Notice of References Cited	Application/Control No. 10/717,107	Applicant(s)/Patent Under Reexamination LU ET AL.	
	Examiner Louis Falasco	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0235717	12-2003	van de Veerdonk et al.	428/694.0TM
	B	US-2004/0053073	03-2004	Lu et al.	428/694.00T
	C	US-6,153,062	11-2000	Saito et al.	204/192.2
	D	US-6,174,597	01-2001	Yusu et al.	428/694B
	E	US-6,830,824	12-2004	Kikitsu et al.	369/13.38
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Park - Effects of Annealing Conditions on the Structure Magnetic Properties of FePt Thin Films - IEEE TRANS ON MAGNETIC Vol. 5 September 1999
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.